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PLUS Search Results for S/N 09864509, Searched November 22, 2004

The Patent Linguistics Utility System (PLUS) is a USPTO automated search system for U.S. Patents from 1971 to the present. PLUS is a query-by-example search system which produces a list of patents that are

most closely related linguistically to the application searched. This search was prepared by the staff of the Scientific and Technical Information Center, SIRA.

6311302
6658614
6324662
6711707
5355369
5682392
5598421
5687312
5708773
5887001
6314539
6380785
6499124
6715105
5412260
5281864
5768289
6122762
5231314
5379302
5448576
5453992
5459737
5497379
5526365
5606566
5677915
5744949
6006343
6073254
6189115
6324614
6408413
6418545
6591387

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6658632
6671840
6701475
6779133
6804725
5627842
6158034
6446230
5706297
6108807
6594802
5991909
6256760
6539520
6813737

09864509_CLS

Most Frequently Occurring Classifications of Patents Returned
From A Search of 09864509 on November 22, 2004

Original Classifications

13	714/726
13	714/727
4	714/28
4	714/30
3	714/729
2	716/4

Cross-Reference Classifications

8	714/727
7	714/724
6	714/726
5	714/734
4	714/30
3	324/158.1
3	326/16
3	714/729
3	714/733
2	327/199
2	702/117
2	714/725
2	714/731
2	714/736
2	714/738

Combined Classifications

21	714/727
19	714/726
8	714/30
8	714/724
6	714/729
5	714/28
5	714/734
4	324/158.1
4	714/733
3	326/16
3	714/731
3	716/4
2	327/199
2	702/117
2	714/725
2	714/736
2	714/738

09864509 CLSTITLES

Titles of Most Frequently Occurring Classifications of Patents Returned

From A Search of 09864509 on November 22, 2004

21 714/727 (13 OR, 8 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive scan
 design (LSSD))
 714/727 ...Boundary scan

19 714/726 (13 OR, 6 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing
 714/726 ..Scan path testing (e.g., level sensitive scan
 design (LSSD))

8 714/30 (4 OR, 4 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING
 714/1 .Reliability and availability
 714/25 ..Fault locating (i.e., diagnosis or testing)
 714/27 ...Particular access structure
 714/30Built-in hardware for diagnosing or testing
 within-system component (e.g., microprocessor
 or test mode
 circuit, scan path)

8 714/724 (1 OR, 7 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 .Digital logic testing

6 714/729 (3 OR, 3 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY

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714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive scan design (LSSD))

714/729 ...Plural scan paths

5 714/28 (4 OR, 1 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

714/100 DATA PROCESSING SYSTEM ERROR OR FAULT HANDLING

714/1 .Reliability and availability

714/25 ..Fault locating (i.e., diagnosis or testing)

714/27 ...Particular access structure

714/28Substituted emulative component (e.g., emulator microprocessor)

5 714/734 (0 OR, 5 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/734 ..Structural (in-circuit test)

4 324/158.1 (1 OR, 3 XR)

Class 324 : ELECTRICITY: MEASURING AND TESTING

324/158.1 MISCELLANEOUS

4 714/733 (1 OR, 3 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/733 ..Built-in testing circuit (BILBO)

3 326/16 (0 OR, 3 XR)

Class 326 : ELECTRONIC DIGITAL LOGIC CIRCUITRY

326/16 WITH TEST FACILITATING FEATURE

3 714/731 (1 OR, 2 XR)

Class 714 : ERROR DETECTION/CORRECTION AND FAULT DETECTION/RECOVERY

714/699 PULSE OR DATA ERROR HANDLING

714/724 .Digital logic testing

714/726 ..Scan path testing (e.g., level sensitive scan

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design_(LSSD))

714/731 ...Clock or synchronization

3 716/4 (2 OR, 1 XR)
 Class 716 : DATA PROCESSING: DESIGN AND ANALYSIS OF
 CIRCUIT OR SEMICONDUCTOR MASK
 716/1 CIRCUIT DESIGN
 716/4 ..Testing or evaluating

2 327/199 (0 OR, 2 XR)
 Class 327 : MISCELLANEOUS ACTIVE ELECTRICAL NONLINEAR
 DEVICES, CIRCUITS, AND SYSTEMS
 327/100 SIGNAL CONVERTING, SHAPING, OR GENERATING
 327/185 ..Particular stable state circuit (e.g.,
 tristable, etc.)
 327/199 ..Circuit having only two stable states (i.e.,
 bistable)

2 702/117 (0 OR, 2 XR)
 Class 702 : DATA PROCESSING: MEASURING, CALIBRATING, OR
 TESTING
 702/108 TESTING SYSTEM
 702/117 ..Of circuit

2 714/725 (0 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 ..Digital logic testing
 714/725 ..Programmable logic array (PLA) testing

2 714/736 (0 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 ..Digital logic testing
 714/736 ..Device response compared to expected
 fault-free response

2 714/738 (0 OR, 2 XR)
 Class 714 : ERROR DETECTION/CORRECTION AND FAULT
 DETECTION/RECOVERY
 714/699 PULSE OR DATA ERROR HANDLING
 714/724 ..Digital logic testing
 714/738 ..Including test pattern generator